

Industry Leading Millisecond Anneal Technology Offers Lowest Thermal Budget Solution



LSA 101 Laser Spike Anneal System

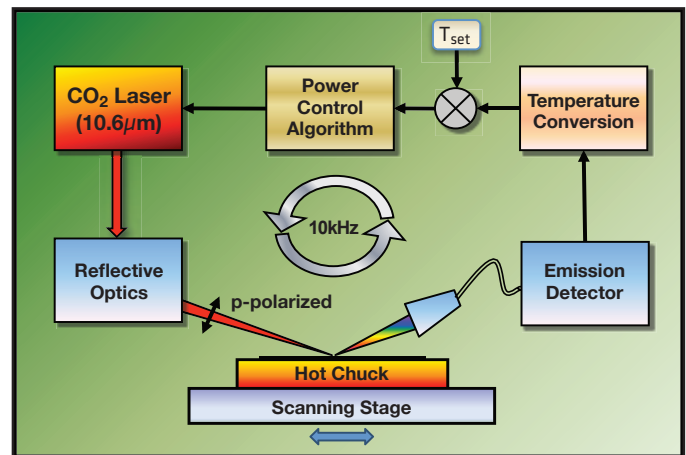
Utilized by leading IDMs and foundries around the globe

- > Ultratech's 300mm LSA101 system is utilized as the preferred technology for high-volume manufacturing of advanced logic devices from the 40nm to 10nm nodes with development at 7nm.
- > Built on the customizable Unity Platform™, the LSA's scanning system has fundamental advantages in uniformity and low-stress processing, which make it readily applicable for current and future device nodes.
- > The LSA101 enables critical millisecond annealing applications that allow customers to maintain high processing temperatures, and thus achieve improved device performance, lower leakage, and improved yield.

Laser Spike Annealing Technology Advantages

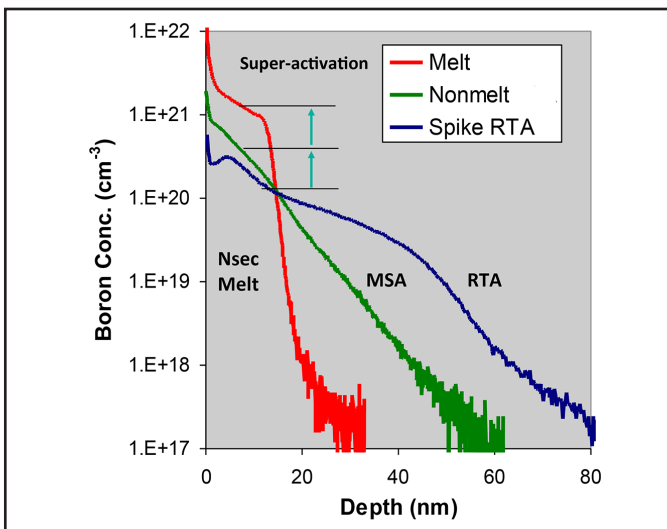
- > Ultratech's laser processing system provides solutions to meet the difficult challenge of fabricating ultra-shallow junction transistors with highly activated source/drain contacts
- > LSA provides a sub-millisecond thermal anneal process at temperatures up to 1350° C, resulting in high activation with minimal dopant diffusion
- > Ultratech's proprietary optical design reduces pattern related within-die temperature variations by >10x as compared to other millisecond annealing systems

LSA Control System



- > Long wavelength p-polarized light at Brewster's angle incidence for optimum within-die uniformity
- > Closed-loop temperature feedback control to maintain tight real-time temperature control
- > Best-in-class pattern insensitivity reduces layout constraints, ideal for the foundry market and for both planer and FinFET devices
- > Localized stress field with flexible dwell time enables low stress processing and reduced wafer breakage

Junction Profile Comparison



Melt annealing results in ultra-shallow, abrupt junction, with above solid solubility activation → better R_s-X_j than MSA

LSA Logic Applications

Planar: Poly & HKMG	Planar: HKMG	FinFET
40/28nm	22/20nm	14/10nm
<ul style="list-style-type: none"> > S/D anneal > S/D ext anneal > SMT 	<ul style="list-style-type: none"> > S/D anneal > S/D ext anneal > SMT > High k anneal > NiSi formation 	<ul style="list-style-type: none"> > S/D anneal > S/D ext anneal > SMT > High k anneal > Re-activation > Ti Silicide formation

LSA is used for an increasing number of applications as devices scale to smaller dimensions with different materials and architectures

Laser Spike Anneal

- Long λ
- Brewsters Angle
- No shadowing or light trapping by Fins

Measured reflectance map

$\Delta T \sim 10^\circ C$

Flash Anneal/Diode

- Short λ
- Near normal incidence
- Can have light trapping by Fins

Measured reflectance map

$\Delta T > 100^\circ C$

Find out more at
www.ultratech.com
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